TEST CONFIGURATION:

1. Vector Network Analyzer, HP Model 8722D

2. Universal Test Fixture Mainframe, Inter-Continental Model TF-3001B

3. Midsection assembly(s), Inter-Continental

P/N A0115386, used on ATC case A and S

P/N A0115388A, used on ATC case B and R

4. Insert assembly(s), Inter-Continental

P/N A0115387, used on ATC case A

P/N A0115387(Modified), used on ATC case S

P/N A0115389A, used on ATC case B and R

5. Calibration Kit, Inter-Continental TRL-3004A

6. RF Test Cable Set, W. L. Gore P/N FE0BN0BM025.0

The test fixture referenced above utilizes 2.4 mm precision transitions and is adjustable to accept the applicable midsection assembly. The insert assembly consists of a 25 mil thick alumina substrate with two 330 mil gold launches. The capacitor test sample was placed in a series thru configuration across a gap at the center of the two launches. The device under test was mounted vertically in the test fixture, such that the electrode orientation was perpendicular to the microstrip. All fixture elements including test cables have been de-embedded and operate in a 50 ohm test environment.

An electrical delay of 7 picoseconds for Case A, 11 picoseconds for Case B and Case R was added in order to place the reference plane at the center of the test insert.

The vector network analyzer used to generate the S-Parameter files has a four-receiver architecture. A full two port TRM/TRL calibration was employed for all measurements.